

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):	Steve Biellak, et al.		
Title:	System and Methods for a Wafer Inspection System Using Multiple Angles and Multiple Wavelength Illumination		
Application No.:	09/891,693	Filing Date:	June 26, 2001
Examiner:	Hoa Q. Pham	Group Art Unit:	2877
Docket No.:	TNCR.179US0	Conf. No.:	1752

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Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

Copies of the documents listed on the accompanying Form PTO-1449 are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

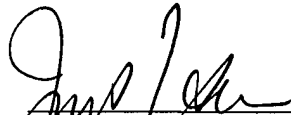
enclosed. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

EXPRESS MAIL NO.:

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February 22, 2005

Respectfully submitted,

  
James S. Hsue  
Reg. No. 29,545

2/22/05  
Date

U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.			Application No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				TNCR.179US0			09/891,693	
				Applicant(s)			Conf. No.	
(Use several sheets if necessary)				Biellak et al.			1752	
				Filing Date			Group	
				June 26, 2001			2877	
<b>U.S. Patent Documents</b>								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	1	6,104,481	Aug. 15, 1000	Sekine et al.				
	2	6,654,111	Nov. 25, 2003	Isozaki et al.				
	3	6,611,328	Aug. 26, 2003	Isozaki et al.				
	4	6,587,192	Jul. 1, 2003	Isozaki et al.				
	5	6,509,964	Jan. 21, 2003	Wiles et al.				
	6	6,292,259	Sep. 18, 2001	Fossey et al.				
<b>U.S. Published Patent Application Documents</b>								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<b>Foreign Patent Documents</b>								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	7	EP 1 318 392 A1	Oct. 17, 2002	EP				
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
Examiner			Date Considered					
<p><b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.</p>								